## **Power MOSFET**

# 30 V, 147 A, Single N-Channel, SO-8 FL

### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

### **Applications**

• CPU Power Delivery, DC-DC Converters

## MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise stated)

Parai	neter		Symbol	Value	Unit
Drain-to-Source Voltage	ge		$V_{DSS}$	30	V
Gate-to-Source Voltage	je		$V_{GS}$	±20	V
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	29.1	Α
Current R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 100°C		18.4	
Power Dissipation R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 25°C	P <sub>D</sub>	2.72	W
Continuous Drain Current $R_{\theta JA} \le 10 \text{ s}$		T <sub>A</sub> = 25°C	I <sub>D</sub>	47.5	Α
(Note 1)	Steady	T <sub>A</sub> = 100°C		30.0	
Power Dissipation $R_{\theta JA} \le 10 \text{ s (Note 1)}$		T <sub>A</sub> = 25°C	P <sub>D</sub>	7.23	W
Continuous Drain Current R <sub>0JA</sub>	State T <sub>A</sub> = 25°C		I <sub>D</sub>	17.1	Α
(Note 2)		T <sub>A</sub> = 100°C	]	10.8	
Power Dissipation R <sub>0JA</sub> (Note 2)		T <sub>A</sub> = 25°C	P <sub>D</sub>	0.93	W
Continuous Drain Current R <sub>θJC</sub>		$T_C = 25^{\circ}C$	I <sub>D</sub>	147	Α
(Note 1)		T <sub>C</sub> =100°C		93	
Power Dissipation R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 25°C	P <sub>D</sub>	69.44	W
Pulsed Drain Current	$T_{A} = 25^{\circ}$	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	442	Α
Current Limited by Pac	kage	T <sub>A</sub> = 25°C	I <sub>Dmax</sub>	100	Α
Operating Junction and	I Storage ∃	Temperature	T <sub>J</sub> , T <sub>STG</sub>	–55 to +150	°C
Source Current (Body Diode)		I <sub>S</sub>	68	Α	
Drain to Source DV/DT		dV/d <sub>t</sub>	6	V/ns	
Single Pulse Drain-to-Source Avalanche Energy $T_J$ = 25°C, $V_{DD}$ = 24 V, $V_{GS}$ = 10 V, $I_L$ = 37 $A_{pk}$ , $L$ = 0.3 mH, $R_G$ = 25 $\Omega$			E <sub>AS</sub>	205	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

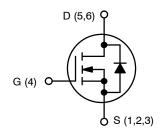
- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.



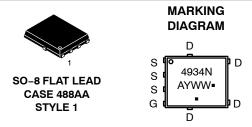
## ON Semiconductor®

### http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
30 V	2.0 m $\Omega$ @ 10 V	447.0
30 V	3.0 m $\Omega$ @ 4.5 V	147 A



**N-CHANNEL MOSFET** 



A = Assembly Location

Y = Year WW = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMFS4934NT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel
NTMFS4934NT3G	SO-8 FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

## THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	1.8	
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	46.0	°C/W
Junction-to-Ambient - Steady State (Note 4)	$R_{\theta JA}$	134.2	
Junction-to-Ambient – (t ≤ 10 s) (Note 3)	$R_{\theta JA}$	17.3	1

- Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
   Surface-mounted on FR4 board using the minimum recommended pad size.

## FLECTRICAL CHARACTERISTICS /T.

Parameter	Symbol	Test Cond	Min	Тур	Max	Unit	
OFF CHARACTERISTICS	•			•	•		•
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /			15.2		mV/°C	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 \text{ V},$ $T_{J} = 25^{\circ}\text{C}$				1.0	
			T <sub>J</sub> = 125°C			10	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub>	<sub>S</sub> = ±20 V			±100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D}$	= 250 μΑ	1.2	1.6	2.2	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				4.6		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 30 A		1.52	2.0	
			I <sub>D</sub> = 15 A		1.52		0
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		2.2	3.0	mΩ
			I <sub>D</sub> = 15 A		2.2		1
Forward Transconductance	9FS	V <sub>DS</sub> = 1.5 V, I <sub>D</sub> = 15 A			80		S
CHARGES, CAPACITANCES & GATE RESIS	TANCE			•	•	•	•
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 15 V			5505		pF
Output Capacitance	C <sub>OSS</sub>				2355		
Reverse Transfer Capacitance	C <sub>RSS</sub>				90		1
Total Gate Charge	Q <sub>G(TOT)</sub>				34		
Threshold Gate Charge	Q <sub>G(TH)</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$			3.8		nC
Gate-to-Source Charge	$Q_{GS}$				13.9		
Gate-to-Drain Charge	$Q_{GD}$				8.1		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 15 V; I <sub>D</sub> = 30 A			76.5		nC
SWITCHING CHARACTERISTICS (Note 6)							
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			20.0		
Rise Time	t <sub>r</sub>				36.2		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				39.3		ns
	1				i e	l e	1

- 5. Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%.
  6. Switching characteristics are independent of operating junction temperatures.

9.4

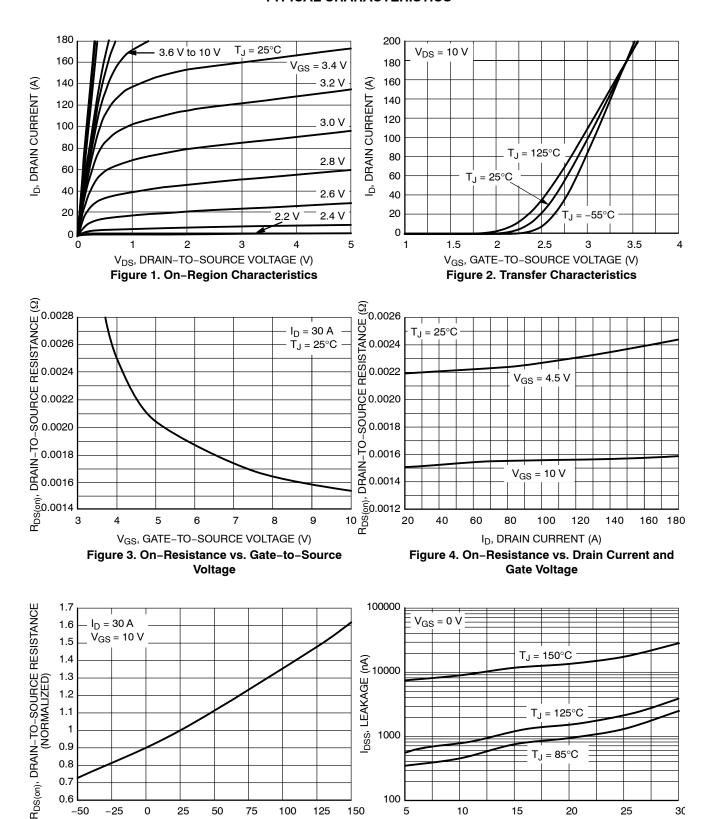
Fall Time

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 6)						
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS} = 10 \text{ V}, V_{DS} = 15 \text{ V}, I_{D} = 15 \text{ A}, R_{G} = 3.0 \Omega$			13.2		
Rise Time	t <sub>r</sub>				33.3		
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$R_{G} = 3.0$	Ω		49.7		ns
Fall Time	t <sub>f</sub>	1			7.8		
DRAIN-SOURCE DIODE CHARACT	ERISTICS						
Forward Diode Voltage	V <sub>SD</sub>	v <sub>GS</sub> = 0 v,	T <sub>J</sub> = 25°C		0.79	1.0	V
			T <sub>J</sub> = 125°C		0.66		
Reverse Recovery Time	t <sub>RR</sub>	V <sub>GS</sub> = 0 V, dIS/dt = 100 A/μs, I <sub>S</sub> = 30 A			59.1		ns
Charge Time	t <sub>a</sub>				28.3		
Discharge Time	t <sub>b</sub>				30.8		
Reverse Recovery Charge	$Q_{RR}$				70		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L <sub>S</sub>	T <sub>A</sub> = 25°C			1.00		nΗ
Drain Inductance	L <sub>D</sub>				0.005		nΗ
Gate Inductance	L <sub>G</sub>				1.84		nH
Gate Resistance	$R_{G}$				0.80		Ω

<sup>5.</sup> Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

### **TYPICAL CHARACTERISTICS**



T<sub>J</sub>, JUNCTION TEMPERATURE (°C)
Figure 5. On–Resistance Variation with
Temperature

V<sub>DS</sub>, DRAIN-TO-SOURCE VOLTAGE (V)

Figure 6. Drain-to-Source Leakage Current vs. Voltage

### TYPICAL CHARACTERISTICS

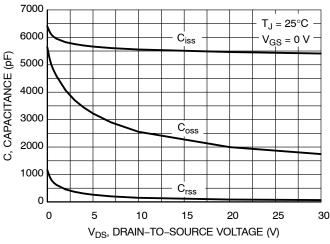


Figure 7. Capacitance Variation

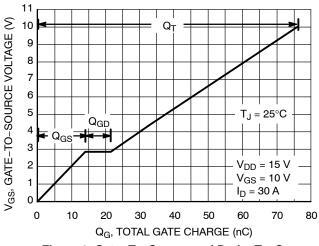


Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge

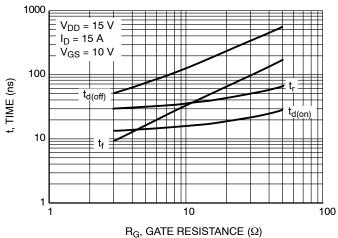


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

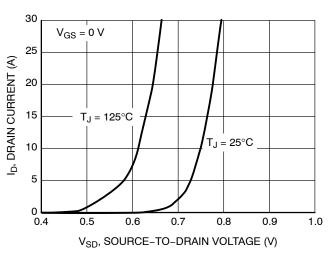


Figure 10. Diode Forward Voltage vs. Current

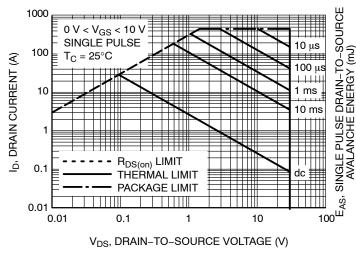
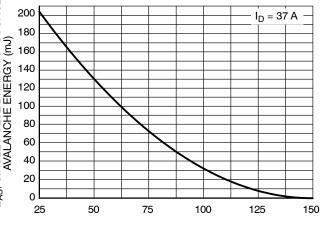


Figure 11. Maximum Rated Forward Biased Safe Operating Area



T<sub>J</sub>, STARTING JUNCTION TEMPERATURE (°C)

Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

## **TYPICAL CHARACTERISTICS**

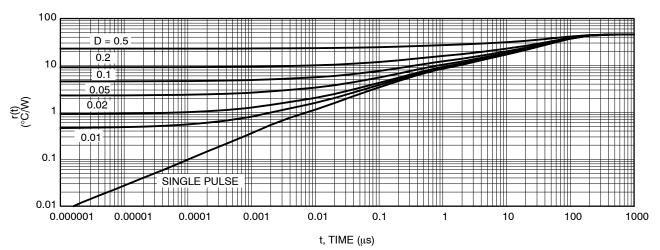


Figure 13. Thermal Response

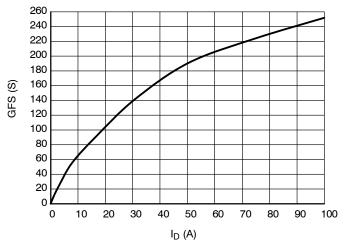
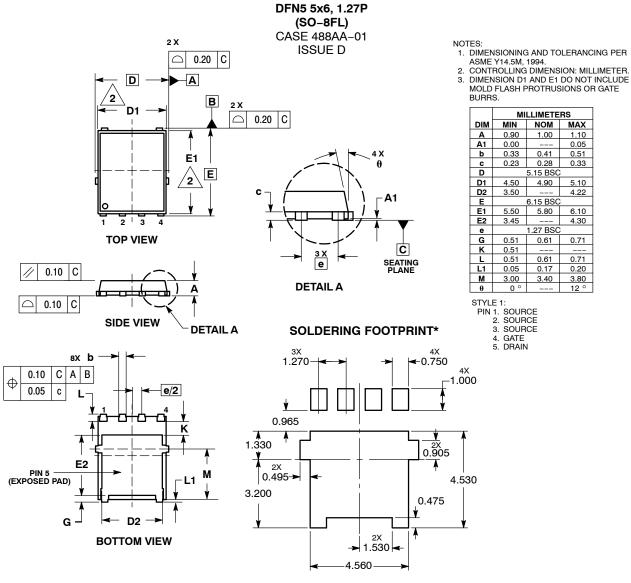


Figure 14. GFS vs. I<sub>D</sub>

### PACKAGE DIMENSIONS



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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